

Abstract Submitted  
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**Counting statistics and entanglement in a disordered free fermion system with a voltage bias**<sup>1</sup> JOSEPH BURG, GREGORY LEVINE, Hofstra University — The Full Counting Statistics is studied for a disordered one-dimensional system of non-interacting fermions with and without a voltage bias. For two unbiased  $L$  site lattices connected at time  $t = 0$ , the charge variance increases as the natural logarithm of  $t$ , following the universal expression  $\langle \delta N^2 \rangle \approx \frac{1}{\pi^2} \log t$ . Since the static charge variance for a length  $l$  region is given by  $\langle \delta N^2 \rangle \approx \frac{l}{\pi^2} \log l$ , this result reflects the conformal invariance and dynamical exponent  $z = 1$  of the disorder-free lattice. With disorder and strongly localized fermions, we have compared our results to a model with a dynamical exponent  $z \neq 1$ , and also a model for entanglement entropy based upon dynamical scaling at the Infinite Disorder Fixed Point (IDFP). The latter scaling, which predicts  $\langle \delta N^2 \rangle \propto \log \log t$ , appears to better describe the charge variance of disordered 1-d fermions. When a bias voltage is introduced, the behavior changes dramatically and the charge and variance become proportional to  $(\log t)^{1/\psi}$  and  $\log t$ , respectively. The exponent  $\psi$  may be related to the critical exponent characterizing spatial/energy fluctuations at the IDFP.

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